

35V N-Channel Enhancement Mode MOSFET

Description

The AP140N03NF uses advanced **APM-SGT V** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 35V$ $I_D = 140A$

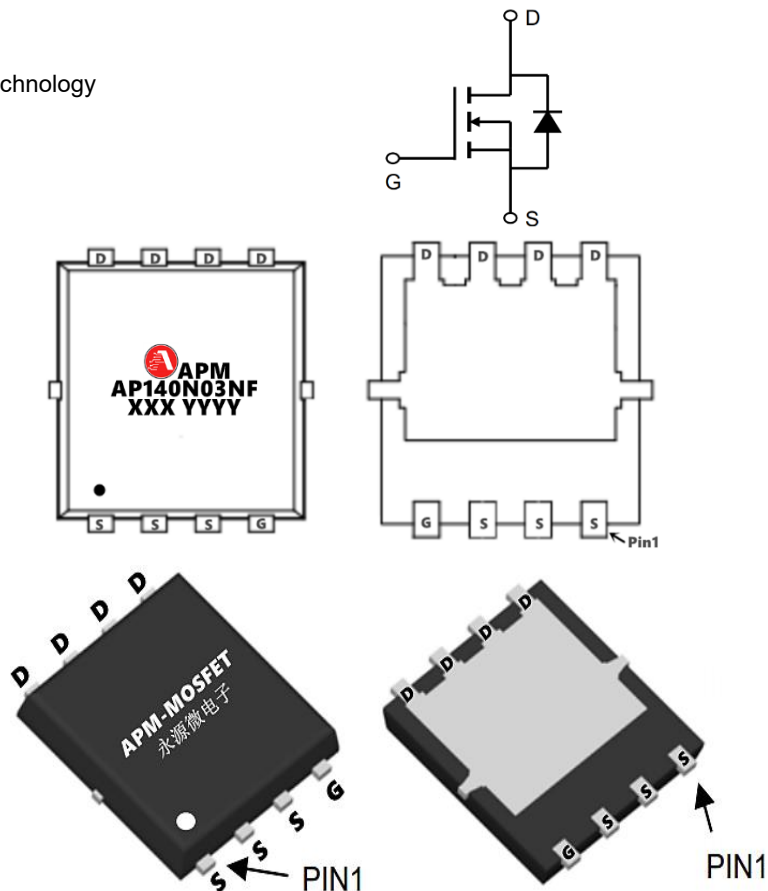
$R_{DS(ON)} < 1.6m\Omega$ @ $V_{GS}=10V$ (**Type: 1.4mΩ**)

Application

Boost driver

Brushless motor

BLDC



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP140N03NF	PDFN5*6-8L	AP140N03NF XXX YYYY	5000

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	35	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_{D@TC=25^\circ C}$	Continuous Drain Current, $V_{GS} @ 10V$	140	A
$I_{D@TC=100^\circ C}$	Continuous Drain Current, $V_{GS} @ 10V$	106	A
I_{DM}	Pulsed Drain Current ²	672	A
E_{AS}	Single Pulse Avalanche Energy ³	180	mJ
I_{AS}	Avalanche Current	54	A
$P_{D@TC=25^\circ C}$	Total Power Dissipation ⁴	81	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient 1	25	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	1.7	$^\circ C/W$

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Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	35	38		V
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 30\text{V}$, $V_{GS} = 0\text{V}$			1.0	μA
IDSS $T_J = 55^{\circ}\text{C}$					5.0	
IGSS	Gate-Body Leakage Current	$V_{DS} = 0\text{V}$, $V_{GS} = \pm 20\text{V}$			± 100	nA
VGS(th)	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	1.2	1.7	2.5	V
RDS(ON)	Static Drain-Source ON-Resistance	$V_{GS} = 10\text{V}$, $I_D = 20\text{A}$		1.4	1.6	m Ω
		$V_{GS} = 4.5\text{V}$, $I_D = 15\text{A}$		2.0	2.7	m Ω
gFS	Forward Transconductance	$V_{DS} = 5\text{V}$, $I_D = 20\text{A}$		85		S
Ciss	Input Capacitance	$V_{GS} = 0\text{V}$, $V_{DS} = 15\text{V}$, $f = 1\text{MHz}$		2554		pF
Coss	Output Capacitance			924		pF
Crss	Reverse Transfer Capacitance			73		pF
Rg	Gate Resistance	$V_{GS} = 0\text{V}$, $V_{DS} = 0\text{V}$, $f = 1\text{MHz}$		1.4		Ω
Qg	Total Gate Charge	$V_{GS} = 0$ to 10V $V_{DS} = 15\text{V}$, $I_D = 20\text{A}$		39.1		nC
Qgs	Gate Source Charge			6.7		nC
Qgd	Gate Drain Charge			5.9		nC
tD(on)	Turn-On DelayTime	$V_{GS} = 10\text{V}$, $V_{DS} = 15\text{V}$ $R_L = 0.75\Omega$, $R_{GEN} = 3\Omega$		10		ns
tr	Turn-On Rise Time			7.3		ns
tD(off)	Turn-Off DelayTime			38.6		ns
tf	Turn-Off Fall Time			16.4		ns
trr	Body Diode Reverse Recovery Time	$I_F = 20\text{A}$, $dI_F/dt = 100\text{A}/\mu\text{s}$		54		ns
Qrr	Body Diode Reverse Recovery Charge			57		nC
IS	Diode Continuous Current	$T_C = 25^{\circ}\text{C}$			140	A
VSD	Diode Forward Voltage	$I_S = 1\text{A}$, $V_{GS} = 0\text{V}$		0.68	1.2	V

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3、The EAS data shows Max. rating . The test condition is $V_{DD} = 32\text{V}$, $V_{GS} = 10\text{V}$, $L = 0.1\text{mH}$, $I_{AS} = 54\text{A}$
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

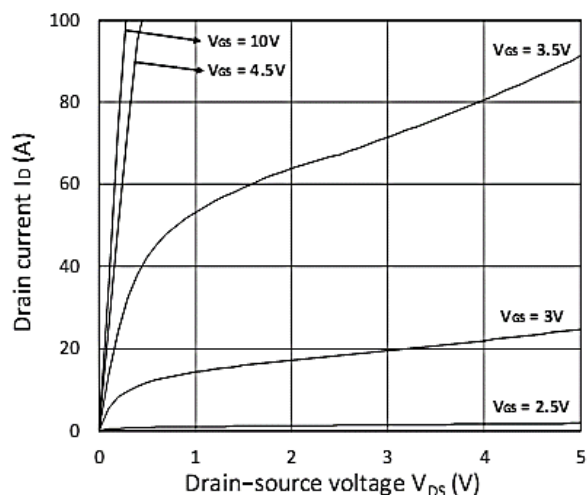


Figure 1. Output Characteristics

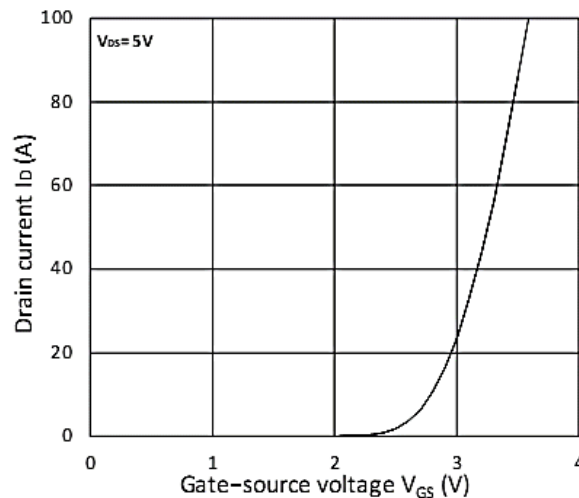


Figure 2. Transfer Characteristics

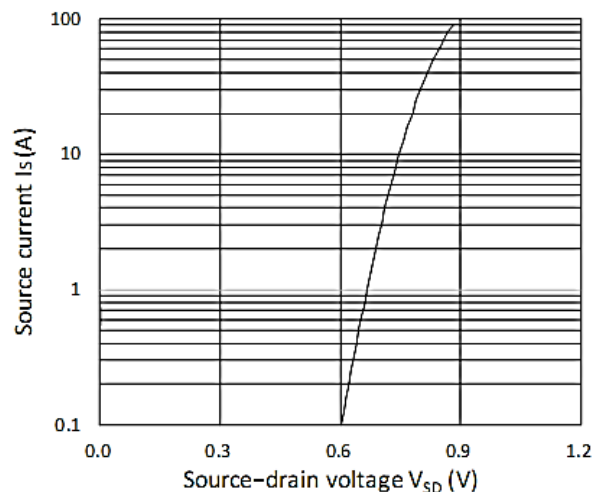


Figure 3. Forward Characteristics of Reverse

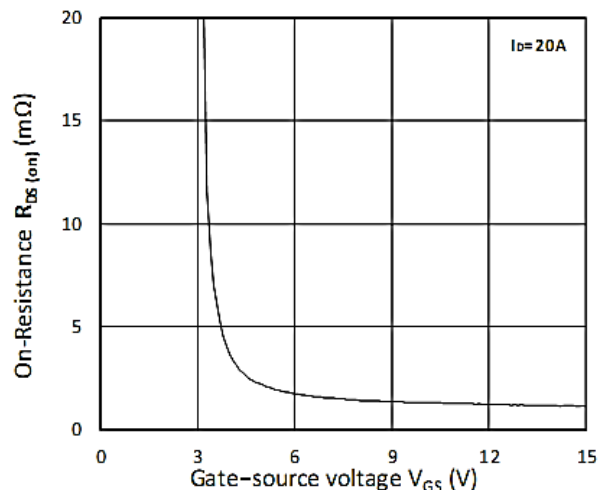


Figure 4. $R_{DS(on)}$ vs. V_{GS}

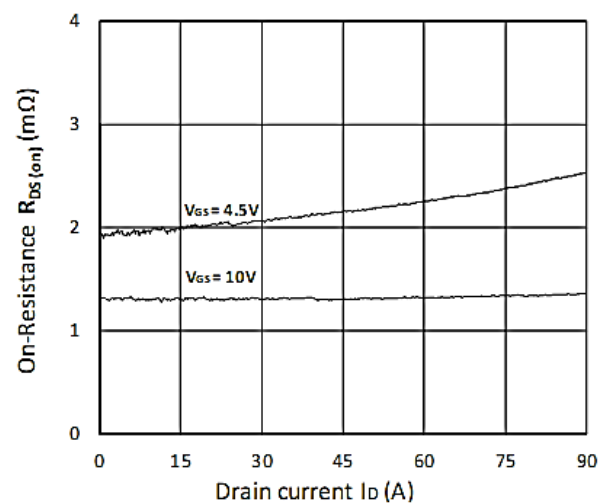


Figure 5. $R_{DS(on)}$ vs. I_D

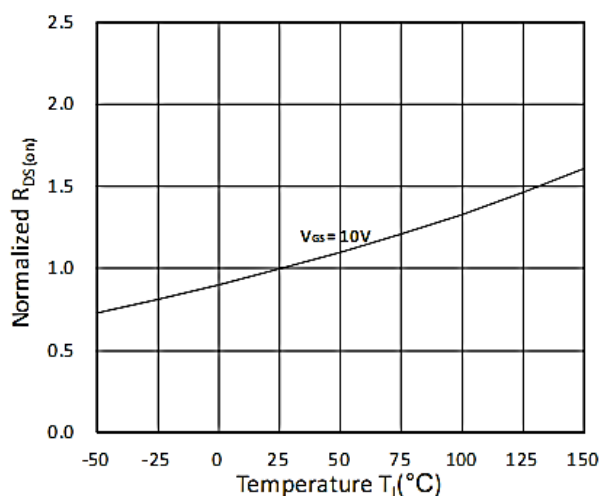


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

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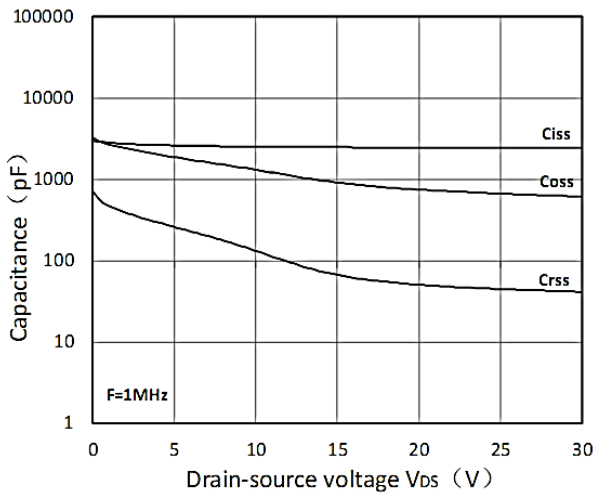


Figure7. Capacitance Characteristics

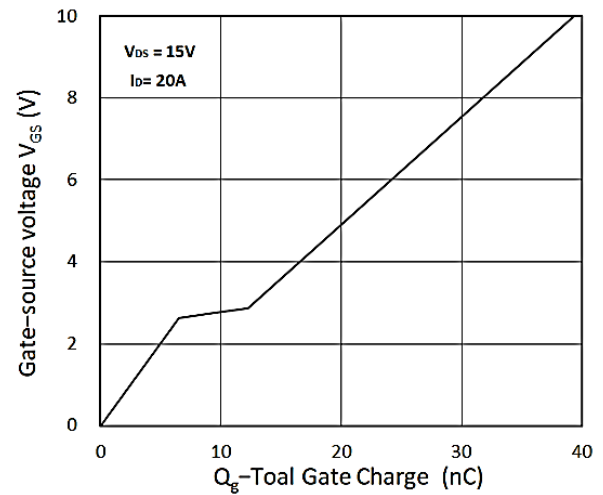


Figure8. Gate Charge Characteristics

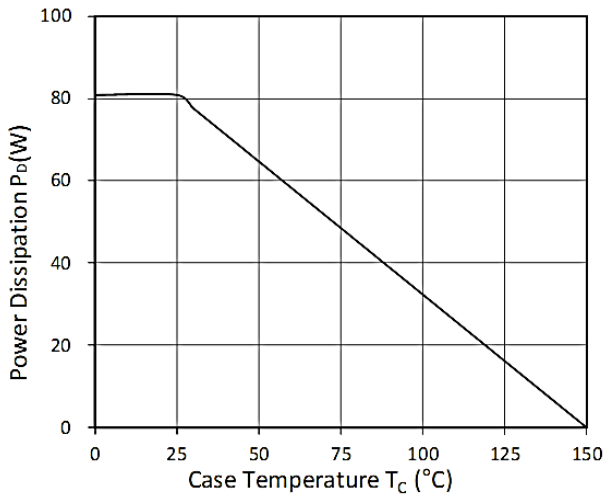


Figure9. Power Dissipation

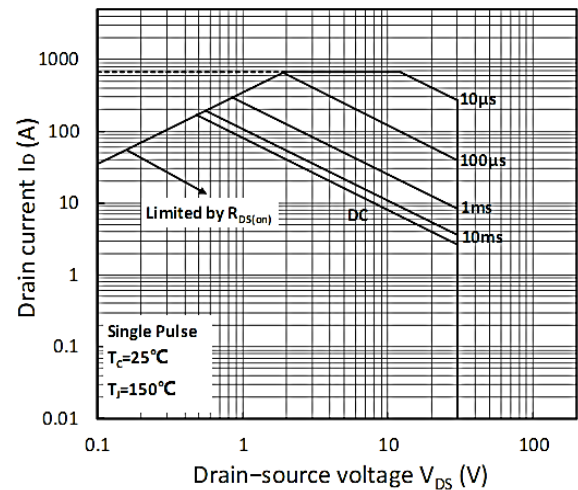


Figure10. Safe Operating Area

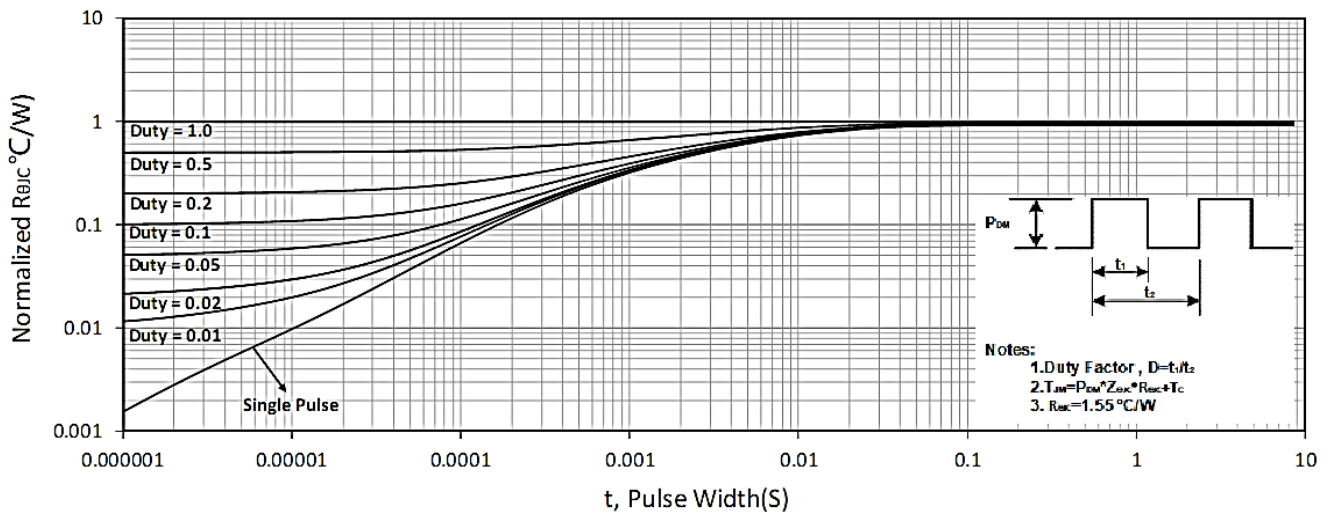
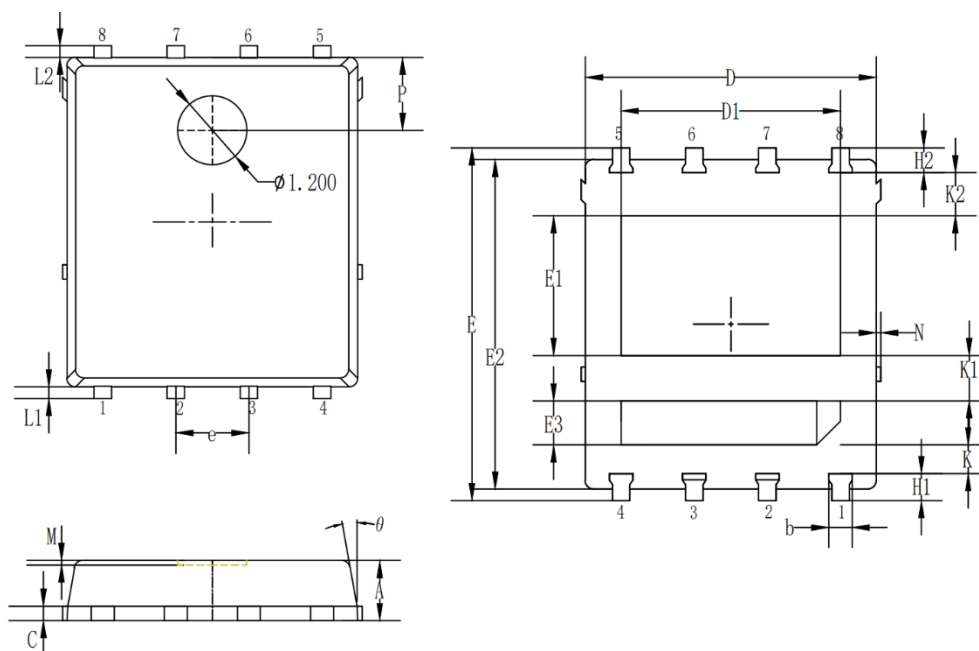


Figure11. Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-PDFN5*6-8L



Symbol	Dim in mm		
	Min	Typ	Max
A	0.9	1.05	1.2
b	0.3	0.4	0.5
C	0.2	0.25	0.35
D	4.9	5.05	5.2
D1/D2	1.51	1.66	1.81
E	5.9	6.1	6.3
E1	3.3	3.5	3.7
E2	5.6	5.75	5.9
e	1.27BSC		
H	0.48	0.58	0.7
K	1.14	1.27	1.4
L	0.54	0.74	0.84
L1/L2	0.1	0.2	0.3
θ	8°	10°	12°
M	0.08REF		
N	0		0.15
P	1.28REF		
d	0.5	0.6	0.7

35V N-Channel Enhancement Mode MOSFET**Attention**

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Edition	Date	Change
REV1.0	2023/9/31	Initial release

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